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Application/Control No.	Applicant(s)/Patent under Reexamination
10/016,184	LEIJTEN ET AL.
Examiner	Art Unit
Daniel Pan	2183

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INT	INTERFERENCE SEARCHED		
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west (pgp uspat jpoabs epoabs derwent ibm) ieee npl 718/104 res. alloc. 711/143 writeback 711/215 microinst.	11/3/2005	DP